



US00D795208S

(12) **United States Design Patent** (10) **Patent No.:** **US D795,208 S**
Sasaki et al. (45) **Date of Patent:** **** Aug. 22, 2017**

(54) **ELECTROSTATIC CHUCK FOR SEMICONDUCTOR MANUFACTURING EQUIPMENT**

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(**) Term: **15 Years**

(21) Appl. No.: **29/553,359**

(22) Filed: **Feb. 1, 2016**

(30) **Foreign Application Priority Data**

Aug. 18, 2015 (JP) 2015-018087

(51) **LOC (10) Cl.** **13-03**

(52) **U.S. Cl.**
USPC **D13/182**

(58) **Field of Classification Search**

USPC D13/182; D15/140

CPC H01L 21/67098; H01L 21/67109; H01L
21/683; H01L 21/6831; H01L 21/6833;
H01L 21/6835; H01L 21/68; H01L 21/67;
B23Q 3/15; B23Q 3/154; B23Q 3/1543;
B23Q 3/1546; B23B 2270/38; G03F
7/70708; G03F 7/707; H02N 13/00;
H02N 15/00

See application file for complete search history.

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(57) **CLAIM**

The ornamental design for an electrostatic chuck for semi-conductor manufacturing equipment, as shown and described.

DESCRIPTION

FIG. 1 is a front view of an electrostatic chuck for semiconductor manufacturing equipment, showing our new design;

FIG. 2 is a rear view thereof;

FIG. 3 is a top plan view thereof;

FIG. 4 is a bottom plan view thereof;

FIG. 5 is a right side view thereof;

FIG. 6 is a left side view thereof;

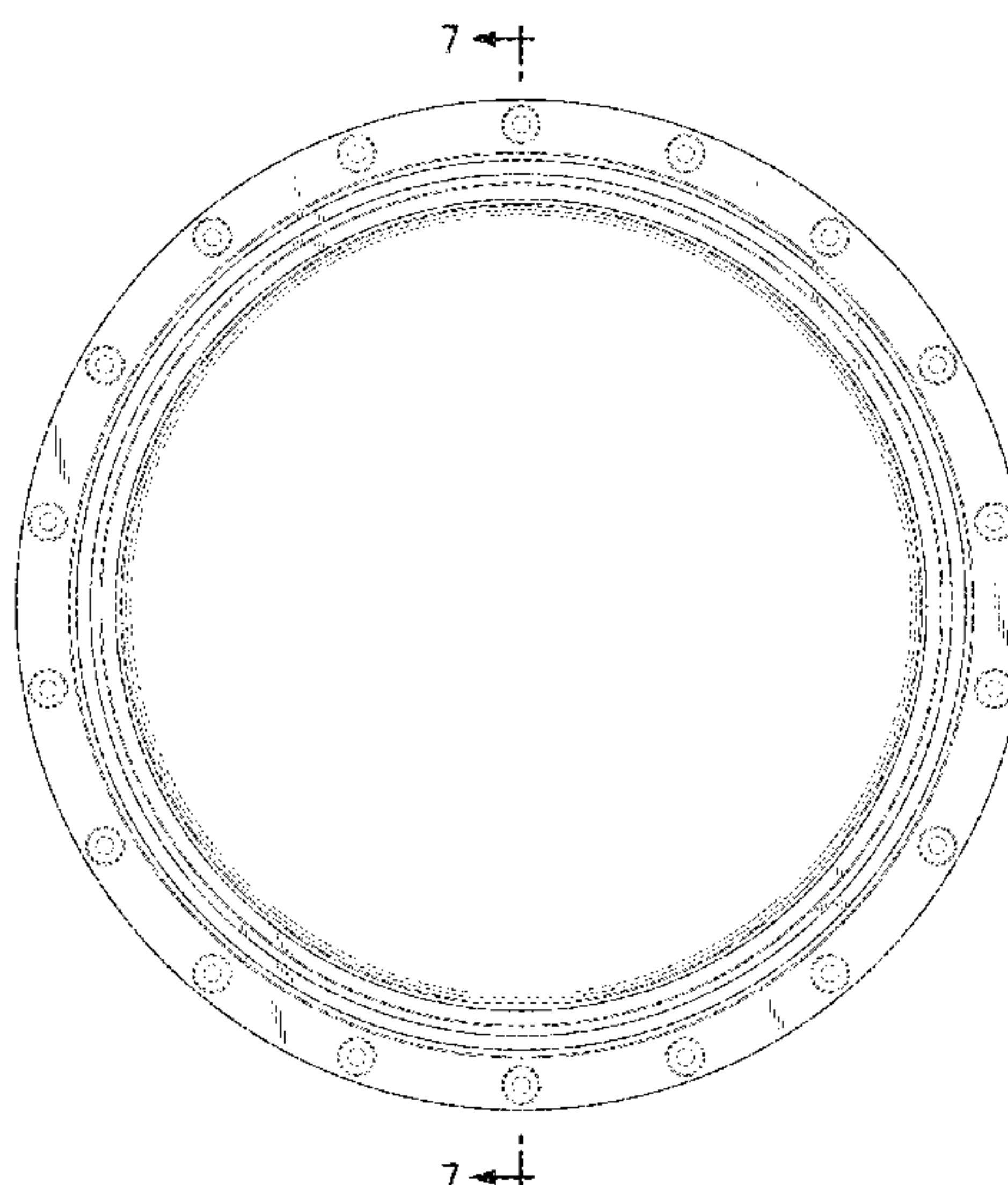
FIG. 7 is a cross sectional view taken along the lines of 7-7 of FIG. 1; and,

FIG. 8 is an enlarged view of a portion taken along lines of 8-8 of FIG. 7.

The features shown in broken lines depict environmental subject matter only and form no part of the claimed design. The alternate long and short dash lines are merely the boundary lines between the claimed parts and the non-claimed parts.

In the FIG. 1, the area surrounded by the alternate long and short dash lines on the electrostatic chuck is not claimed.

1 Claim, 8 Drawing Sheets



(56)

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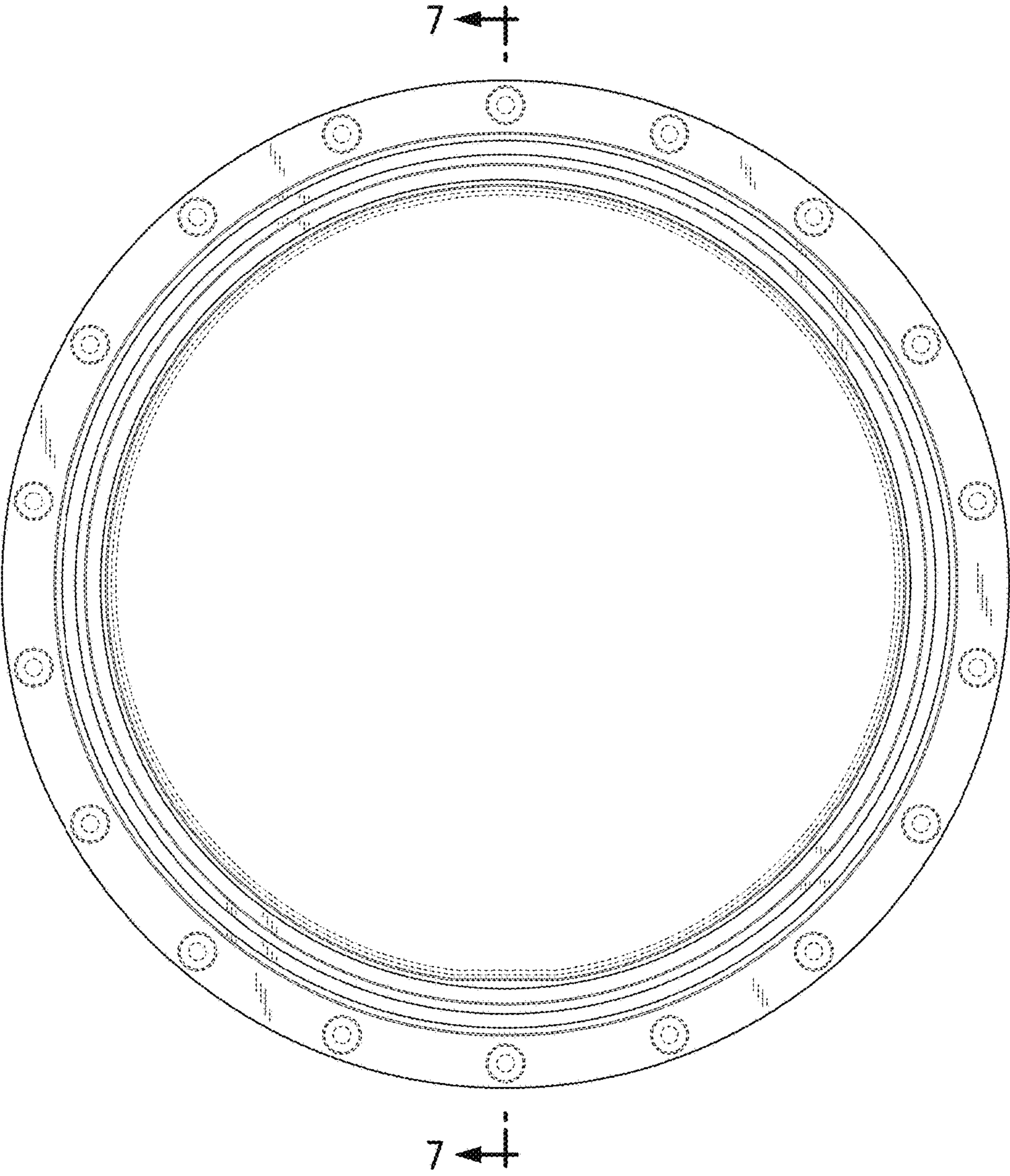


FIG. 1

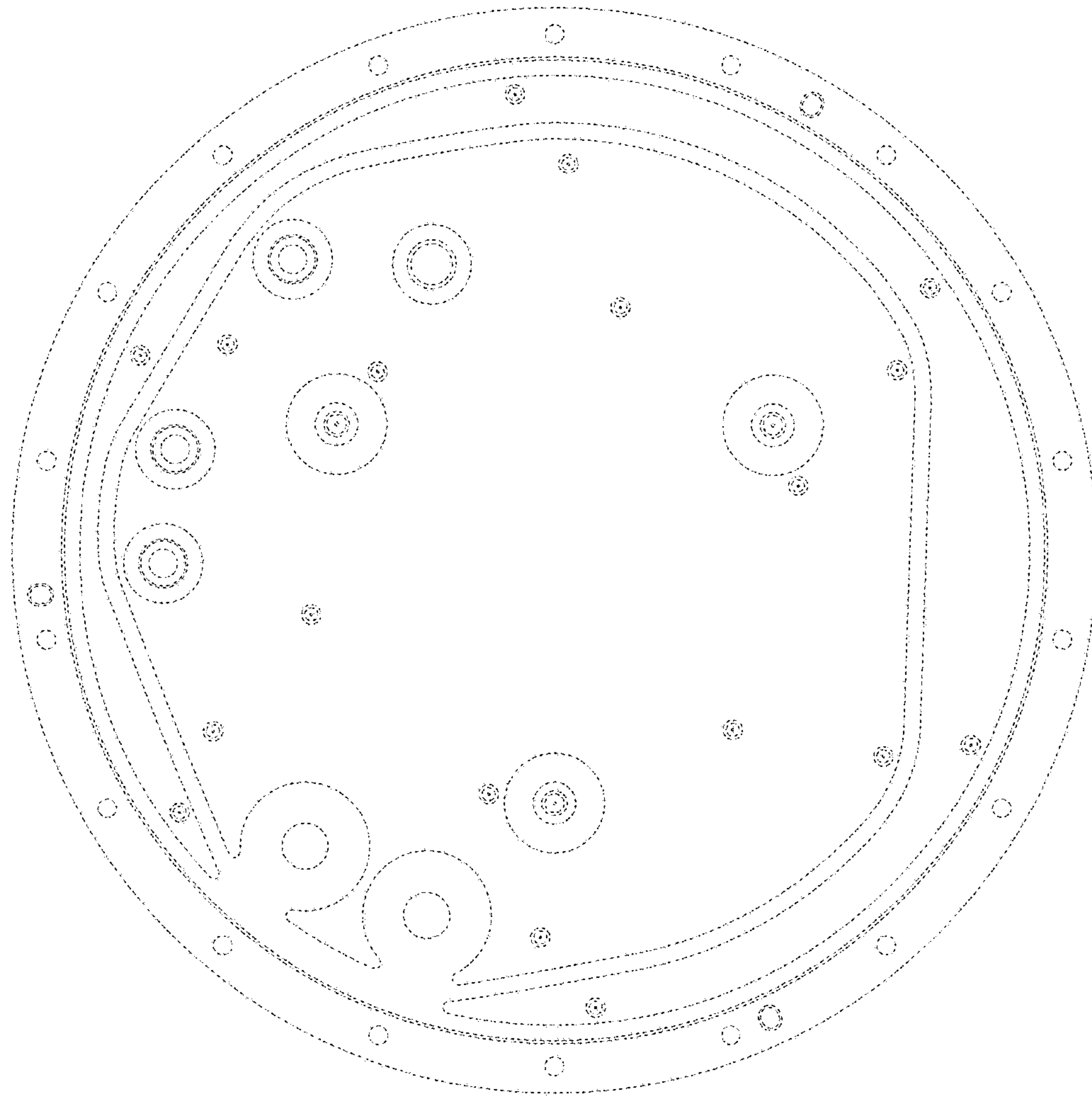


FIG. 2

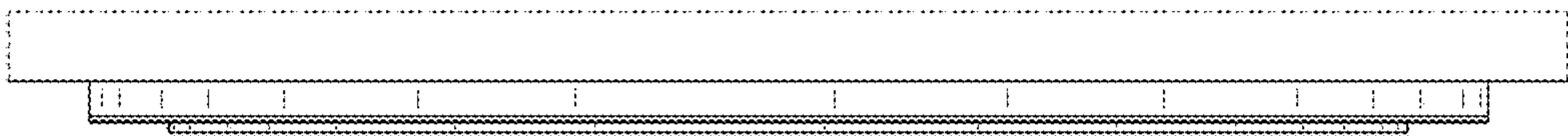


FIG. 3

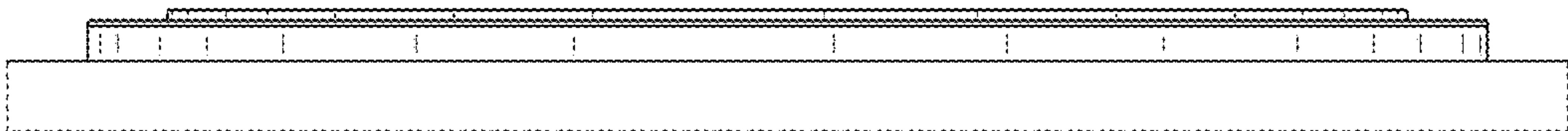


FIG. 4

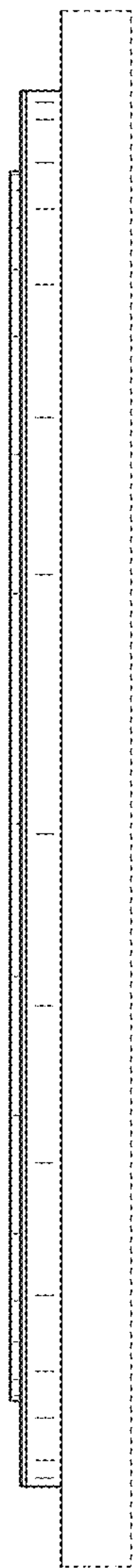


FIG. 5

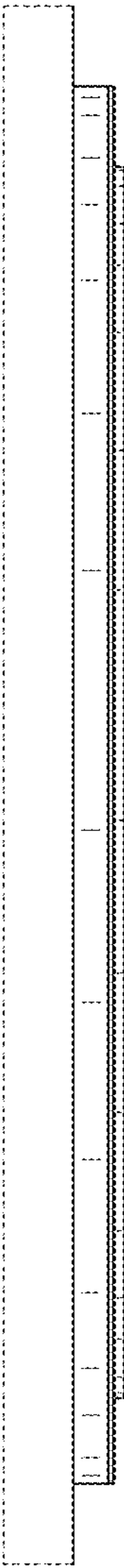


FIG. 6

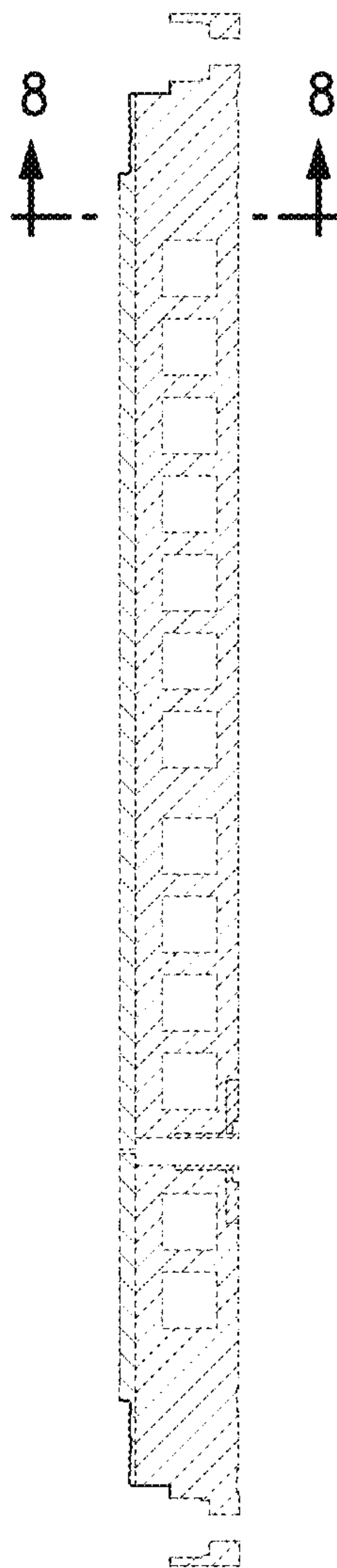


FIG. 7

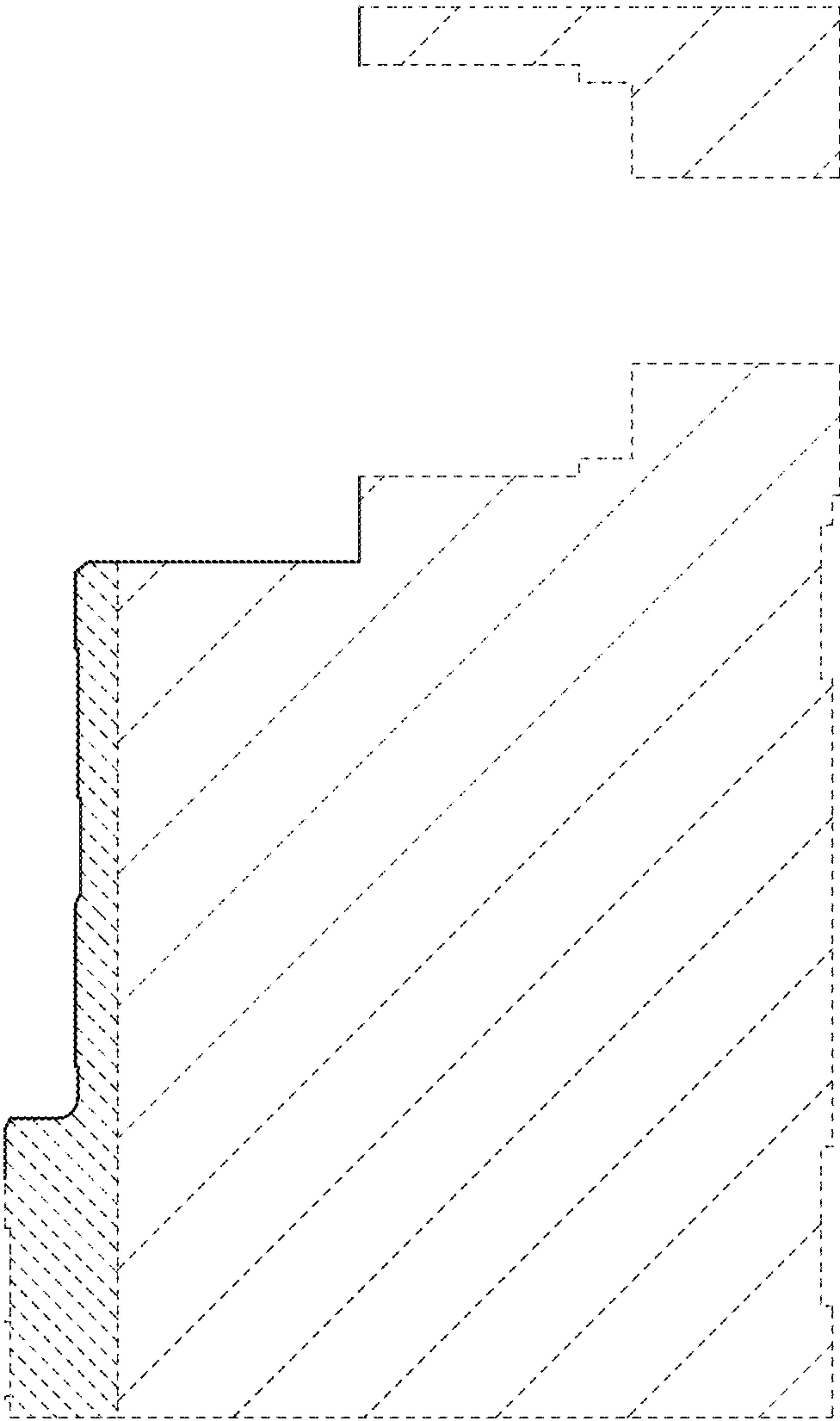


FIG. 8